

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/451,939	MIAO ET AL.	
	Examiner	Art Unit	
	Michael Brannock	1649	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		6/2/2006	WJ
Seq database, interference specialist C. Tsang		6/2/2006	WJ